

Module Design, Manufacture and Test

Reliability

Long-term system reliability is our major focus for our customers systems. Reliability is achieved by insuring that the device is designed, manufactured and tested accurately leading to reduced defective (short term and long term) devices being shipped to the field. Failures in the field reduces customer satisfaction and increases the total cost of ownership. Our goal at WEDC is to increase the profit and success for our customers.

RoHS Compliant Modules

White Electronic Designs Corporation (WEDC) is committed to environmental care in all its facilities. We are committed to complying with all environmental laws and regulations applicable to our activities and to our products. WEDC maintains detailed Lead-Free / RoHS information to enable our customers to cross reference and find valid alternatives.

Module Characterization

Complete correlation with customers test results on DIMM devices can be established. Test correlation has been verified in many cases to the exact memory cell of failure on the individual module DRAM components. Other memory module suppliers in many cases have not been able to fail these same devices using their internal test algorithms and procedures.

Based on customer's needs, WEDC provides modules validated by Intel, AMD, Tyan, etc.

Module Validation

WEDC modules are validated on multiple platforms with full parametric characterization. Our lab capabilities include documentation for IBIS models extracted from a schematic or physical layout.

Failure Analysis

WEDC has extensive experience in performing failure analysis on a wide range of parts and products and identifying a wide range of failure mechanisms.

Extended Temperature Testing

WEDC has extensive experience and capability in extended temperature testing. WEDC can provide guard-banded extremes of temperature and voltage as well as temp-cycle simulations.

Customized Test Patterns

Typical WEDC test flow includes:

- ◆ Four-corner production test
- ◆ Min-max voltage and temp (0-70°C); guard band test temps to $\pm 10^{\circ}\text{C}$
- ◆ Contact and Leakage
- ◆ Operating Current
- ◆ Walk Shift Patterns
- ◆ March G
- ◆ Walk increment
- ◆ March X, Y, C
- ◆ Stress test
- ◆ SPD

Configuration, Source, Lot & Revision Control

Upon request WEDC can provide component revision tracking/control; configuration control; or module design revision tracking/control.

Part numbering system incorporates silicon supplier source control.

Available serialization and lot traceability.

Product Change Notification (PCN)

PCN's are provided for any data book electrical specification changes (fit, form and function).

